

# FAQ



**Subject : Reliability of GUVx-S1xSD & GUVx-C1xSD**

**Date : 2012. 04. 23.**

1) Examination standard

Items	Symbol	Min.	Max.	Units	Test Conditions
Dark Current	Id	-	1	nA	Vr = 0.1 V
Photo Current	Iph	70	130	%	Vr = 0 V

2) Test Conditions & Results

Items	Test Conditions		Result	Standardization
	GUVx-S1xSD	GUVx-C1xSD		
Preconditioning Test	Bake(125 °C, 24hrs) + Soak + 3 Reflow  Soak : 60 °C 60% RH, 40 hrs  MSL 3 level	Bake(125 °C, 24hrs) + Soak + 3 Reflow  Soak : 85 °C 85% RH, 168 hrs  MSL 1 level	Pass	JESD22-A113
HTS (High Temperature Storage)	85 °C, 1,000 hrs	85 °C, 1,000 hrs	Pass	JESD22-A103
LTS (Low Temperature Storage)	-30 °C, 1,000 hrs	-30 °C, 1,000 hrs	Pass	JESD22-A119
TS (Thermal Shock)	-30 °C/85 °C, 15 Cycles	-30 °C/125 °C, 15 Cycles	Pass	JESD22-A106
PCT (Pressure Cooker Test)	121 °C, 100 % RH, 29.7 psi, 4 hrs	121 °C, 100 % RH, 29.7 psi, 24 hrs	Pass	JESD22-A102
ESD (HBM)	Class 1A : 300 V	Class 1A : 400 V	Pass	JESD22 A-114